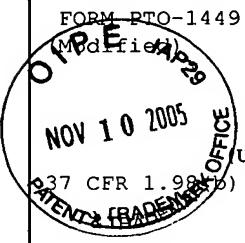


**Section 2. Form PTO-1449 (Modified)**

Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

 <b>FORM PTO-1449</b> <b>Modified</b> <b>NOV 10 2005</b> <b>Use Several Sheets if Necessary</b> <b>37 CFR 1.98(b)</b>	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE							ATTY. DOCKET NO. <b>PA-5343-RFB</b>	SERIAL NO. <b>10/647,642</b>	
	INFORMATION DISCLOSURE STATEMENT BY APPLICANT							APPLICANT <b>David Ernest Hartley</b>		
	FILING DATE August 25, 2003							GROUP <b>3738</b>		

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		PATENT NUMBER					ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5	3	8	7	2	3	5	2/1995	Chuter	
	AB	5	5	6	2	7	2	6	10/1996	Chuter	
	AC	5	5	7	5	8	1	7	11/1996	Martin	
	AD	5	6	3	4	9	4	1	6/1997	Winston et al.	
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	AL	6	2	2	4	6	0	9	5/2001	Ressemann et al.	
	AM	6	3	3	1	1	9	1	12/2001	Chobotov	

**FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION**

		DOCUMENT NUMBER					PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
											YES	NO
	AN	9	5	2	0	6	0	5	10/1995	WIPO		
	AO	0	0	8	0	7	3	3	11/1995	EPO		
	AP	9	8	5	3	7	6	1	12/1998	WIPO		
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AZ	U.S. Patent Application Publication No. 2004/0082990; Hartley.; 4/2004										
BA	International Search Report; PCT/US03/26561; 12/2003										

**EXAMINER**
**DATE CONSIDERED**

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.